

11045 U.S. PRO  
10/033373  
10/24/01

PATENT NUMBER and  
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10053373	FILING DATE 10/24/2001	CLASS 378	SUBCLASS	GAU 2882	EXAMINER
----------------------	---------------------------	--------------	----------	-------------	----------

\*\*APPLICANTS: Fanton Jeffrey; Uhrich Craig; Koppel Louis;

\*\*CONTINUING DATA VERIFIED:

THIS APPLN CLAIMS BENEFIT OF 60/261,154 01/11/2001

\*\* FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met	<input type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO	TWI-13310
Verified and Acknowledged Examiners's initials			
TITLE : X-ray reflectance measurement system with adjustable resolution			
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
TERMINAL DISCLAIMER		Primary Examiner		
		PREPARED FOR ISSUE		
		Application Examiner		
WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.				

FILED WITH:  DISK (CRF)  CD-ROM  
(Attached in pocket on right inside flap)